


<b>Search Notes</b> 	<b>Application/Control No.</b> 10688763	<b>Applicant(s)/Patent Under Reexamination</b> YIP ET AL.
	<b>Examiner</b> Wang, Ben C	<b>Art Unit</b> 2196

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	125 - combined with text search	5/20/2007	Ben C. Wang <i>BW</i>

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Google, IEEE, ACM Databases Search	5/20/2007	Ben C. Wang <i>BW</i>

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>